

Report of the 1946 Spring Meeting of the American Society for X-Ray and Electron Diffraction

THE 1946 spring meeting of the American Society for X-Ray and Electron Diffraction was held at Silver Bay, New York, June 10–15. The following papers were given:

- E. W. Hughes, California Institute of Technology. **X-ray examinations of some synthetic oxygen-carrying chelate compounds.**
- N. Davidson and J. Hillier, RCA Laboratories, Princeton, New Jersey. **Single crystal electron diffraction by micro-crystalline materials.**
- M. Schneider, and I. Fankuchen, Polytechnic Institute of Brooklyn. **Some D.D.T. analogues.**
- R. Pepinsky, Alabama Polytechnic Institute. **Some aspects of electronic instrumentation in x-ray diffraction studies.**
- A. de Bretteville, Jr., Laboratory for Insulation Research, Massachusetts Institute of Technology. **Oscillographic study of the dielectric properties of barium titanate.**
- F. G. Chesley, Central Research Laboratories, Inc., Red Wing, Minnesota. **The design and construction of an electron diffraction camera and its application to the selenium rectifier problem.**
- W. Parrish and E. Cisney, Philips Laboratories, Inc., Irvington-on-Hudson, New York. **Collimator systems and filter techniques for x-ray powder cameras.**
- R. W. G. Wyckoff, National Institute of Health, Bethesda, Maryland. **Structure of macro molecular crystals by use of the electron microscope.**
- M. A. Peacock, University of Toronto. **Structure of rickardite, $\text{Cu}_{4-x}\text{Te}_2$.**
- E. W. Hughes and W. N. Lipscomb, Jr., California Institute of Technology. **The structure of methyl ammonium chloride.**
- M. J. Buerger, G. Klein, and G. Hamburger, Massachusetts Institute of Technology. **The structure of nepheline.**
- M. L. Huggins, Kodak Research Laboratories, Rochester, New York. **Equations for various types of summations.**
- M. J. Buerger, Massachusetts Institute of Technology. **The interpretation of Harker syntheses.**
- D. Wrinch, Department of Physics, Smith College. **Fourier transforms and complex organic crystals.**
- D. Harker, General Electric Research Laboratory. **Micro-waves (short wave radio) and scale models in determining crystal structures.**
- R. Pepinsky, Alabama Polytechnic Institute. **Summation of two-dimensional Fourier series by electronic means.**
- A. D. Booth, Birkbeck College, University of London. **Fourier methods and machines in England 1940–1946.**
- E. W. Hughes, California Institute of Technology. **Punched card methods in x-ray and electron diffraction calculations.**
- D. McLachlan, Jr., American Cyanamid Company, Stamford, Connecticut. **A new numbered strip method for summing Fourier series.**
- M. J. Buerger, Massachusetts Institute of Technology. **Derivative crystal structures.**
- F. N. Rhines, Carnegie Institute of Technology. **The thesis that order-disorder changes are ordinary phase changes.**
- E. J. Armstrong, Bell Telephone Laboratories. **Application of the Barrett technique to some problems concerning non-metallic crystals.**
- D. D'Eustachio, Collman Manufacturing Company, Erie, Pennsylvania. **Surface layers and mosaic structure in some valence crystals.**
- L. Sturkey, Dow Chemical Company, Midland, Michigan. **Refraction and absorption effects in electron diffraction.**
- J. Karle, Naval Research Laboratory, Washington, D.C. **Theory of electron scattering by oriented long chain molecules.**
- J. W. Hickman, Westinghouse Research Laboratories, East Pittsburgh, Pennsylvania. **Electron diffraction studies of oxide film formation on W, Mo, and W, Mo, Ni and Cr alloys.**
- E. A. Gulbransen, Westinghouse Research Laboratories, East Pittsburgh, Pennsylvania. **Deviation of lattice parameters of thin oxide films by electron diffraction analysis.**
- E. I. Alessandrini, General Electric Research Laboratory. **Oxide films on chromium.**

Mimeographed abstracts of these papers are being mailed to the members of the society. Anyone wishing an abstract of any paper should write to the author of that paper.

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